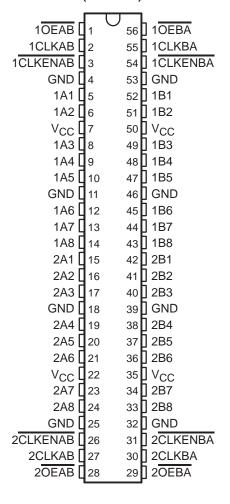
- **Members of the Texas Instruments** Widebus™ Family
- State-of-the-Art *EPIC-IIB™* BiCMOS Design Significantly Reduces Power Dissipation
- Latch-Up Performance Exceeds 500 mA Per **JEDEC Standard JESD-17**
- Typical V_{OLP} (Output Ground Bounce) < 1 V at $V_{CC} = 5 \text{ V}, T_A = 25^{\circ}\text{C}$
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB
- High-Drive Outputs (-32-mA I_{OH}, 64-mA I_{OI})
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package **Using 25-mil Center-to-Center Spacings**

description

The 'ABT16470 are 16-bit registered transceivers that contain two sets of D-type flip-flops for temporary storage of data flowing in either direction. The 'ABT16470 can be used as two 8-bit transceivers or one 16-bit transceiver. Separate clock (CLKAB or CLKBA) and output-enable (OEAB or OEBA) inputs are provided for each register to permit independent control in either direction of data flow.

To avoid false clocking of the flip-flops, clock enable (CLKEN) should not be switched from high to low while CLK is high.

SN54ABT16470 . . . WD PACKAGE SN74ABT16470 . . . DGG OR DL PACKAGE (TOP VIEW)



To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16470 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ABT16470 is characterized for operation from -40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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SN54ABT16470, SN74ABT16470 16-BIT REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS SCBS085E - FEBRUARY 1991 - REVISED MAY 1997

FUNCTION TABLE†

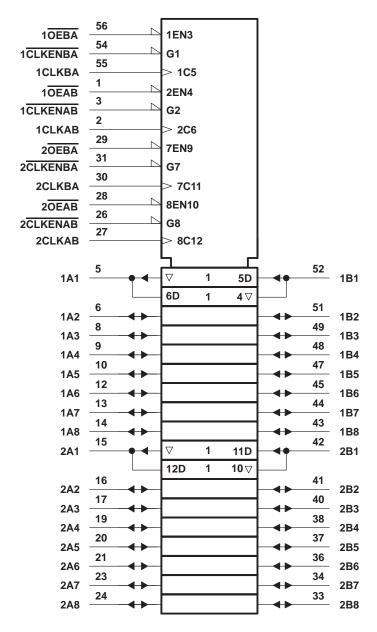
| | OUTPUT | | | |
|---------|------------|------|---|------------------|
| CLKENAB | CLKAB | OEAB | Α | В |
| Н | Х | Χ | Χ | Z |
| Х | Χ | Н | Χ | Z |
| L | L | L | Χ | в ₀ ‡ |
| L | \uparrow | L | L | L |
| L | \uparrow | L | Н | Н |

[†] A-to-B data flow is shown: B-to-A flow is similar but uses CLKENBA, CLKBA, and OEBA.



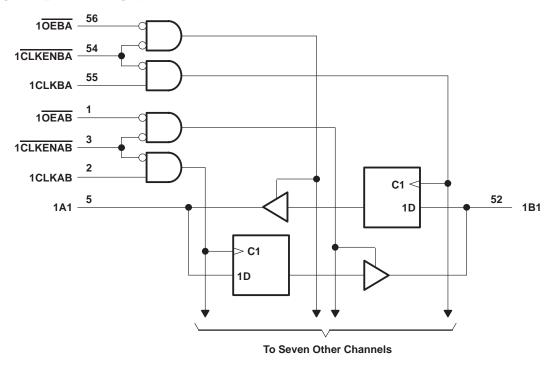
[‡]Output level before the indicated steady-state input conditions were established

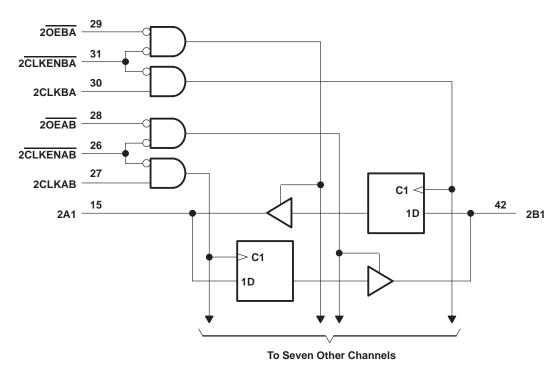
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)







absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

| Supply voltage range, V _{CC} | –0.5 V to 7 V |
|---|-----------------|
| Input voltage range, V _I (except I/O ports) (see Note 1) | |
| Voltage range applied to any output in the high or power-off state, VO | –0.5 V to 5.5 V |
| Current into any output in the low state, I _O : SN54ABT16470 | 96 mA |
| SN74ABT16470 | 128 mA |
| Input clamp current, I _{IK} (V _I < 0) | –18 mA |
| Output clamp current, I_{OK} ($V_O < 0$) | |
| Package thermal impedance, θ _{JA} (see Note 2): DGG package | |
| DL package | |
| Storage temperature range, T _{stg} | –65°C to 150°C |

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

| | | | SN54ABT16470 | | SN74ABT16470 | | UNIT |
|--|---|-----------------|--------------|-----|--------------|-----|------|
| | | | MIN | MAX | MIN | MAX | UNIT |
| Vcc | Supply voltage | | 4.5 | 5.5 | 4.5 | 5.5 | V |
| V _{IH} High-level input voltage | | | 2 | EM | 2 | | V |
| VIL | V _{IL} Low-level input voltage | | | 0.8 | | 0.8 | V |
| V _I Input voltage | | 0 0 | VCC | 0 | VCC | V | |
| IOH High-level output current | | 40, | -24 | | -32 | mA | |
| loL | IOL Low-level output current | | 200 | 48 | | 64 | mA |
| Δt/Δν | Input transition rise or fall rate | Outputs enabled | B | 10 | | 10 | ns/V |
| TA | Operating free-air temperature | | – 55 | 125 | -40 | 85 | °C |

NOTE 3: Unused pins (input or I/O) must be held high or low to prevent them from floating.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

SN54ABT16470, SN74ABT16470 16-BIT REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

SCBS085E - FEBRUARY 1991 - REVISED MAY 1997

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | Т | A = 25°C | ; | SN54ABT16470 | | SN74ABT16470 | | UNIT | |
|--------------------|--|---|----------------------------------|-----|----------|-------|-----------------|-------------|--------------|------|------|--|
| PA | RAWETER | 1EST COR | ADITIONS | MIN | TYP | MAX | MIN | MAX | MIN | MAX | UNII | |
| VIK | | $V_{CC} = 4.5 \text{ V},$ | I _I = -18 mA | | | -1.2 | | -1.2 | | -1.2 | V | |
| | | $V_{CC} = 4.5 \text{ V},$ | $I_{OH} = -3 \text{ mA}$ | 2.5 | | | 2.5 | | 2.5 | | | |
| \/a | | $V_{CC} = 5 V$, | $I_{OH} = -3 \text{ mA}$ | 3 | | | 3 | | 3 | | \ \ | |
| VOH | | V _{CC} = 4.5 V | $I_{OH} = -24 \text{ mA}$ | 2 | | | 2 | | | | | |
| | | VCC = 4.5 V | $I_{OH} = -32 \text{ mA}$ | 2* | | | | | 2 | | | |
| Val | | V _{CC} = 4.5 V | $I_{OL} = 48 \text{ mA}$ | | | 0.55 | | 0.55 | | | V | |
| VOL | | VCC = 4.5 V | $I_{OL} = 64 \text{ mA}$ | | | 0.55* | | | | 0.55 | V | |
| V _{hys} | | | | | 100 | | | 14 | | | mV | |
| ١. | Control inputs | V 55V | VI – Vaa ar CND | | | ±1 | | ₹ ±1 | | ±1 | | |
| tį | A or B ports | V _{CC} = 5.5 V, | $V_I = V_{CC}$ or GND | | | ±100 | 4 | ±100 | | ±100 | μΑ | |
| lozh [‡] | | $V_{CC} = 5.5 \text{ V},$ | V _O = 2.7 V | | | 50 | | 50 | | 50 | μΑ | |
| loz _L ‡ | | $V_{CC} = 5.5 \text{ V},$ | V _O = 0.5 V | | | -50 | ² QC | - 50 | | -50 | μΑ | |
| loff | | $V_{CC} = 0$, | V_I or $V_O \le 4.5 \text{ V}$ | | | ±100 | 4 | | | ±100 | μΑ | |
| ICEX | | V _{CC} = 5.5 V, V _O = 5.5 V | Outputs high | | | 50 | | 50 | | 50 | μА | |
| IO§ | | V _{CC} = 5.5 V, | V _O = 2.5 V | -50 | -100 | -200 | -50 | -200 | -50 | -200 | mA | |
| | | V _{CC} = 5.5 V, | Outputs high | | | 2 | | 2 | | 2 | | |
| Icc | A or B ports | | Outputs low | | | 35 | | 35 | | 35 | mA | |
| | $V_I = V_{CC}$ or G | $V_I = V_{CC}$ or GND | Outputs disabled | | | 2 | | 2 | | 2 | | |
| ΔICC¶ | | V _{CC} = 5.5 V, One in Other inputs at V _{CC} | | | | 0.5 | | 0.5 | | 0.5 | mA | |
| Ci | Control inputs V _I = 2.5 V or 0.5 V | | | 3 | | | | | | pF | | |
| Cio | A or B ports | $V_0 = 2.5 \text{ V or } 0.5 \text{ V}$ | | | 8.5 | | | | | | pF | |

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)

| | | V _{CC} = 5 V, T _A = 25°C | | SN54ABT16470 | | SN74ABT16470 | | UNIT |
|------------------|--|---|-----|--------------|-------|--------------|-----|------|
| | | | | MIN | MAX | MIN | MAX | |
| fclock | Clock frequency | 0 | 150 | 0 | 150 | 0 | 150 | MHz |
| t _W # | Pulse duration, CLKAB or CLKBA high or low | 3.3 | | 3.3 | 16.10 | 3.3 | | ns |
| t _{su} | Setup time, data before CLKAB↑ or CLKBA↑ | 4 | | 4 | 7. | 4 | | ns |
| th | Hold time, data after CLKAB↑ or CLKBA↑ | 1 | | Ŷ1 | | 1 | | ns |

[#]This parameter is characterized, but not production tested.



[†] All typical values are at $V_{CC} = 5 \text{ V}$.

[‡] The parameters IOZH and IOZL include the input leakage current.

[§] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

This is the increase in supply current for each input that is at the specified TTL voltage level rather than V_{CC} or GND.

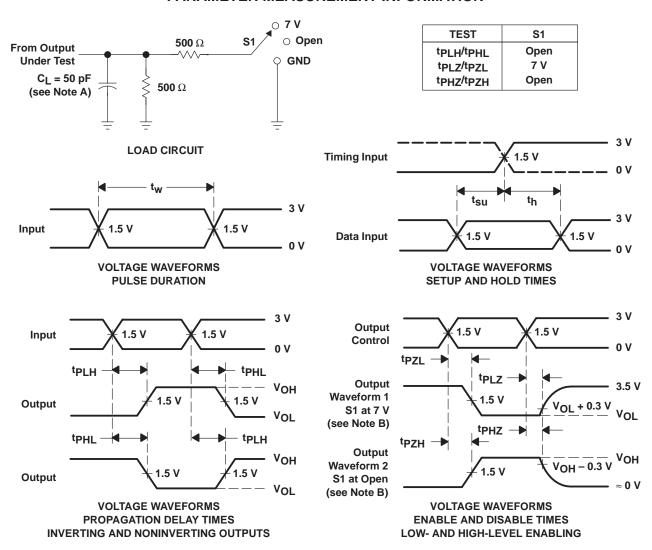
SN54ABT16470, SN74ABT16470 16-BIT REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

SCBS085E - FEBRUARY 1991 - REVISED MAY 1997

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

| PARAMETER | FROM (INPUT) | TO (OUTPUT) | V ₍ | CC = 5 V 4 = 25°C | ', ; | SN54AB | Γ16470 | SN74AB1 | Γ16470 | UNIT |
|------------------|-----------------|----------------|----------------|----------------------|---------|--------|--------|---------|---------|------|
| | (1141 01) | (0011 01) | MIN | TYP | MAX | MIN | MAX | MIN | MIN MAX | |
| fmax | | | 150 | | | 150 | | 150 | | MHz |
| t _{PLH} | CLK | A or B | 1.4 | 3.1 | 4.8 | 1.4 | 5.1 | 1.4 | 4.9 | |
| ^t PHL | | AUIB | 1.3 | 3.2 | 4.6 | 1.3 | 5.1 | 1.3 | 4.9 | ns |
| ^t PZH | ŌĒ | A or B | 1 | 3.1 | 4.3 | 1 | 5 | 1 | 4.9 | no |
| t _{PZL} | OE | AUIB | 1.2 | 3.6 | 5.8 | 1.2 | 6.9 | 1.2 | 6.8 | ns |
| ^t PHZ | ŌĒ | A or B | 1.9 | 3.7 | 4.9 | 1.9 | 6 | 1.9 | 5.5 | 20 |
| ^t PLZ |] 06 | AOIB | 1.6 | 3.3 | 4.8 | 1.6 | 5.4 | 1.6 | 5.3 | ns |
| ^t PZH | - OLIVEN | A or D | 1 | 3.4 | 4.6 | & 1 | 5.8 | 1 | 5.7 | |
| t _{PZL} | CLKEN | A or B | 1.2 | 3.9 | 6 | 1.2 | 7.3 | 1.2 | 7.2 | ns |
| ^t PHZ | CLKEN | A or B | 1.7 | 3.9 | 5.2 | 1.7 | 6.2 | 1.7 | 5.8 | no |
| t _{PLZ} | CLKEN | AUID | 1.5 | 3.6 | 5.3 | 1.5 | 5.5 | 1.5 | 5.4 | ns |

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_{Q} = 50 Ω , t_{f} \leq 2.5 ns, t_{f} \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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